

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Kenichiro SHINOI, et al.
Application No.: New PCT National Stage Application
Filed: July 18, 2005
For: ACCURACY MEASUREMENT APPARATUS AND ACCURACY
MEASUREMENT METHOD FOR CHANNEL QUALITY REPORT

PRELIMINARY AMENDMENT

Honorable Commissioner of
Patents and Trademarks
Washington, DC 20231

Sir:

Please amend the above application as follows: